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Trap-assisted large gain in Cu₂O/C₆₀ hybrid ultraviolet/visible photodetectors

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Photomultiplication-type ultraviolet (UV)/visible photodetectors (PDs) are demonstrated in an electrodeposited Cu₂O/C₆₀ hybrid structure. These simple organic/inorganic hybrid PDs exhibit external quantum efficiencies (EQEs) of $1.1 \times 10^4\%$ under illumination of 365 nm UV light at -3 V, indicating a large gain of photocurrent for these devices. Such an EQE is one of the highest values among the reported organic/inorganic hybrid PDs at the same voltage. Cu₂O and C₆₀ are found to play different roles in realizing the photomultiplication. Copper vacancies are proposed as the defects in the electrodeposited Cu₂O layers, which can trap photogenerated holes. Such trapped holes will trigger the injection of multiple electrons and hence result in the photocurrent gain of the devices while C₆₀ primarily acts as a light absorption media to provide free holes. *Published by AIP Publishing.*
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Photodetectors (PDs) have received much attention due to their wide applications in industrial, military, biological, and environmental applications.^{1–3} There are typically two types of PDs, e.g., photodiode- and photomultiplication (PM)-type PDs. For a photodiode-type PD, the external quantum efficiency (EQE) is generally lower than unity due to its limited light absorption efficiency, electron-hole pair (or exciton) dissociation efficiency, and charge-carrier collection efficiency.^{4–9} On the other hand, the PM-type PD exhibits an EQE much higher than unity due to the mechanism that one incident photon can trigger more than one hole (or electron) flowing across the PD, indicating a photocurrent gain of this device.^{10–12} The active materials of the PM-type PDs can be either inorganic or organic ones. Impact ionization is generally considered as the gain mechanism of inorganic PM-type PDs, and such a mechanism generally requires a high voltage.^{13–15} However, impact ionization could not happen in organic materials due to their large binding energy and disordered structure,^{16,17} even though large gain has been observed in organic PDs, which is attributed to the trap-assisted incensement of charge carrier injection.^{18–20} Due to the thin organic layer used in these devices, the driving voltage was dramatically reduced. Recently, the organic/inorganic hybrid devices have attracted broad interest for PM-type PDs.^{21–25} In addition to their similar lower driving voltage as compared with organic counterparts, the energy band structures of these PDs can be easily manipulated by simply revising the molecule structure of the organic materials, providing us unmatched design flexibility. In these devices, photogenerated electrons are trapped in n-type metal oxides, which reduce hole injection barrier from the cathode and then produce a photocurrent gain. There are rare reports on PM-type PD based on p-type inorganic material/organic hybrid structure. Chen *et al.*²⁶ have demonstrated a PD with an EQE

as high as 8000% at 350 nm and -4.5 V in a p-type CdTe nanoparticles blended polymer-fullerene matrix. However, the driving voltage is desired to be further decreased from the point of view of energy consumption.

Cu₂O is one of the most promising p-type photovoltaic materials owing to its direct bandgap structure, high absorption coefficient, non-toxicity, and cost-efficient production routes.^{27–29} The theoretical calculated power conversion efficiency of a Cu₂O solar cell is about 20%.³⁰ However, the highest efficiency obtained up to now is significantly lower.^{30–32} This is attributed to the low quality of the prepared Cu₂O layer that contains a lot of defects (Refs. 33–37) and the short transport length of minority carrier (electrons in Cu₂O).^{38,39} However, these defects may act as the traps for photogenerated charge carriers and then manipulate the photoconductivity of the devices, which makes it potentially applicable in PM-type photodetectors. In this work, Cu₂O electrodeposited on ITO substrate is firstly used in PM-type ultraviolet/visible (UV/Vis) PDs. The simple Cu₂O/C₆₀ hybrid device shows a high EQE of $1.1 \times 10^4\%$ at 365 nm and a low voltage of -3 V. Such an EQE is one of the highest values among the reported organic/inorganic hybrid PDs at the same wavelength and voltage.^{21–26}

Cu₂O layers were synthesized by an electrodeposition method on ITO coated glass substrates with a sheet resistance of 15 Ω/sq in 0.4 M CuSO₄ and 3 M lactic acid solution. The pH value of the solution was regulated to 12 by NaOH and the color of the solution turned from light blue into dark blue. The deposition was carried out in a configured glass cell at 60 °C, in which the ITO substrate, a platinum plate, and an Ag/AgCl electrode in a saturated KCl solution served as the working electrode, the counter electrode, and the reference electrode, respectively. During the electrodeposition, the potential was set to be of -0.3 V vs the reference electrode and the duration of the depositions was varied from 60 to 150 s. Devices were fabricated by thermal evaporating

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60 nm C₆₀, 10 nm 4,7-diphenyl-1,10-phenanthroline (Bphen), and 100 nm Al in sequence onto the Cu₂O layers in a vacuum chamber at a pressure of 5×10^{-4} Pa without breaking vacuum, and substrates were held at room temperature during this process. Deposition rate and layer thickness were monitored *in situ* using oscillating quartz monitors. Evaporation rates were kept at 1 Å/s for C₆₀ and Bphen and 10 Å/s for Al cathode. X-ray diffraction (XRD) patterns were measured with a Rigaku D/Max-2500 diffractometer using Cu K α radiation ($\lambda = 1.54$ Å). Absorption spectra were recorded on a Shimadzu UV-3101 spectrophotometer in a transmittance arrangement with a bare ITO glass as the reference. Scanning electron microscopy (SEM) images were measured by a Philips-FEI XL30-SFEG scanning electron microscopy. X-ray photoelectron spectroscopy (XPS) measurements were taken on an ESCALAB-MKII 250 photoelectron spectrometer (VG Co.) with Al K α X-ray radiation as the source for excitation. Current-voltage (*J-V*) characteristics of the devices were measured with a Keithley 2400 source meter. The EQE spectra were performed with a Stanford SR803 lock-in amplifier under monochromatic illumination.

Figures 1(a)–1(d) show the SEM images of Cu₂O layers on ITO substrates with deposition times of 60, 90, 120, and 150 s and their corresponding cross-sectional ones in (Figs. 1(e)–1(h)), respectively. No complete Cu₂O film but Cu₂O particles are formed within the deposition time of 150 s. SEM images of these Cu₂O particles with a large magnified scale are displayed in Fig. S1 (in Ref. 40). The Cu₂O particles deposited for 60 s are uniform and semisphere with an average diameter of about 2 μ m. When the deposition time increases to 90 s, both the morphology and density of Cu₂O particles are almost unchanged, but the diameter increases to about 3 μ m. Further increase in the deposition time results in an increase of the particle density with the same diameter but a gradual change of the morphology from semisphere to truncated octahedra. During this deposition period, the height of the particles always keeps at about 1 μ m, indicating that the growth of Cu₂O particle is primary in the landscape orientation.

XRD patterns of the Cu₂O layers with different deposition times are plotted in Fig. S2 (in Ref. 40). Three peaks at 2θ of ca. 29.78°, 36.81°, and 42.89° are observed, which can

be assigned to the (110), (111), and (200) planes of Cu₂O crystal, respectively, indicating that the Cu₂O has the pure cuprous structure (JCPDF No. 05-0667). No other phase, such as CuO, is detected.

Cu₂O/C₆₀ hybrid devices were fabricated based on these different Cu₂O layers. Figure S3 (in Ref. 40) shows the cross-sectional SEM images of the entire device. It can be found that the Cu₂O particles are fully covered by the upper organic and Al layers. Figure 2 depicts the EQE spectra of the Cu₂O/C₆₀ hybrid devices with different Cu₂O layers at zero bias. The EQE spectra have the same sharp with a response peak at about 360 nm and a shoulder at about 450 nm, suggesting that these devices can be applied as UV/Vis PDs. Among these PDs, the device with 90 s Cu₂O exhibits the highest EQE of about 28%, corresponding to a response of 82 mA/W at 360 nm.

Figure 3 illuminates the absorption spectra of 90 s Cu₂O, 60 nm C₆₀, and their hybrid films. Although both Cu₂O and C₆₀ absorb at the UV/Vis region, the absorption intensity of Cu₂O is significantly lower than that of C₆₀ due to its low coverage, as shown in Fig. 1. The absorption of the Cu₂O/C₆₀ hybrid film is almost the sum of the two individuals, and the abnormal spectra near 300 nm should be attributed to the experiment error due to the high absorption of ITO in this region and the difference between ITO substrates. Due to the lower absorption of Cu₂O, the response of the Cu₂O/C₆₀ hybrid devices may primarily come from C₆₀. To validate this hypothesis, a reference device with the structure of ITO/MoO₃ (2 nm)/C₆₀ (60 nm)/Bphen (10 nm)/Al is fabricated. In this device, MoO₃ forms a Schottky contact with C₆₀ and the photocurrent is only contributed from the absorption of C₆₀.⁴¹ Interestingly, the shape of EQE spectrum of this device is the same to those of the Cu₂O/C₆₀ hybrid devices, as shown in Fig. S4 (in Ref. 40). This indicates that the response of the hybrid devices primarily results from the absorption of C₆₀.

Figure S5 (in Ref. 40) draws the dark current of the Cu₂O/C₆₀ hybrid devices with different Cu₂O layers. It can be found that all the devices have a similar dark current curve with a typical diode character. The rectification ratio of these devices reaches to the order of 10^3 at ± 3 V. It should be noted that the dark current is higher than other

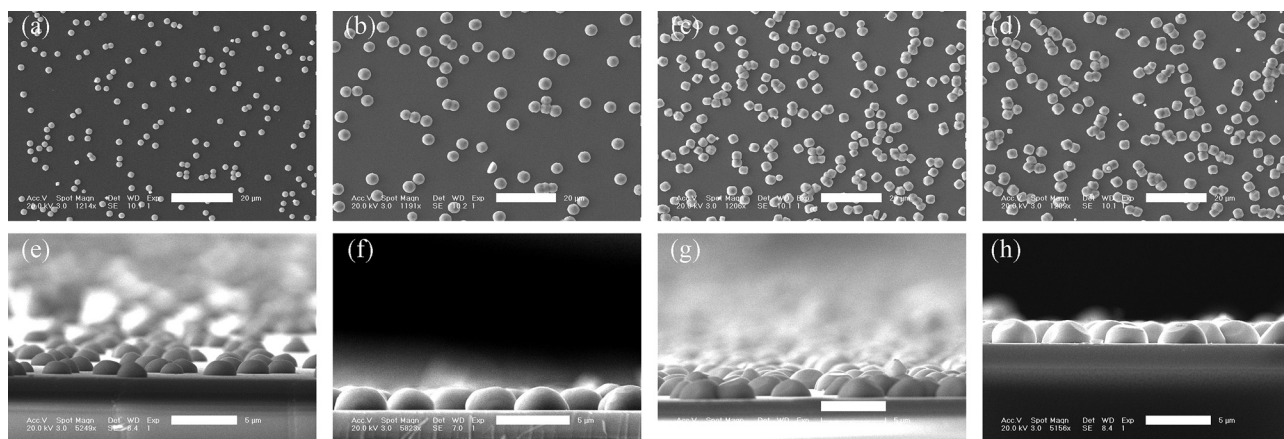


FIG. 1. SEM images of Cu₂O layer on ITO substrates with deposition times of (a) 60, (b) 90, (c) 120, and (d) 150 s and their corresponding cross-sectional SEM images (e)–(h), respectively. The scale bars in the upper and lower images indicate a length of 20 and 5 μ m, respectively.

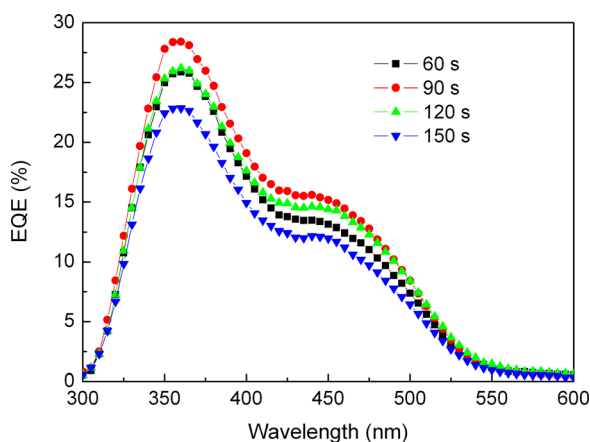


FIG. 2. EQE spectra of the ITO/Cu₂O/C₆₀/Bphen/Al hybrid devices with different Cu₂O layers at zero bias.

reported organic/inorganic hybrid PDs,^{21–26} which is attributed to the direct contact between ITO and C₆₀.

The photocurrent of a PD can increase with the applied reverse voltage, and the difference between the photodiode- and PM-type PDs is that the photocurrent tends to saturate at a low voltage with an EQE less than unity for the former while it can increase continuously with the voltage to an EQE dramatically higher than unity for the latter. The photocurrent of the Cu₂O/C₆₀ hybrid devices is measured under illumination of a 365 nm UV light with an intensity of 1.2 mW/cm². The calculated EQEs as a function of voltage are plotted in Fig. 4. The EQEs at zero bias are in the range of 22%–28%, which are coinciding with the ones measured from their EQE spectra. The EQEs increase rapidly with the voltage and exceed 100% at a low voltage of only −1 V. All the devices achieve a maximum EQE of about $1.1 \times 10^4\%$ at −3 V, corresponding to a photocurrent gain of 110, except the device with a 20 s Cu₂O. This finding indicates that these hybrid devices can be used as high efficient PM-type PDs, and this EQE is one of the highest values among the reported organic/inorganic hybrid PDs at the same wavelength and voltage.^{21–26}

The response speed is another merit-of-figure for a PD. Figure S6 (in Ref. 40) shows the photocurrent transient measurement by periodically switching on and off the 365 nm UV light with an intensity of 1.2 mW/cm² at zero bias. The rising and decaying rates of the photocurrent are pretty rapid

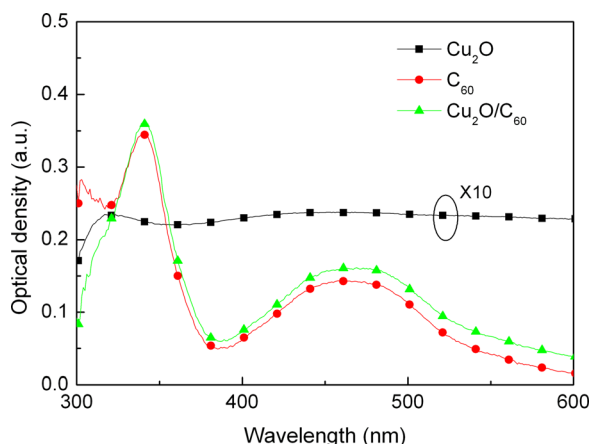


FIG. 3. Absorption spectra of 90 s Cu₂O, 60 nm C₆₀, and their hybrid films.

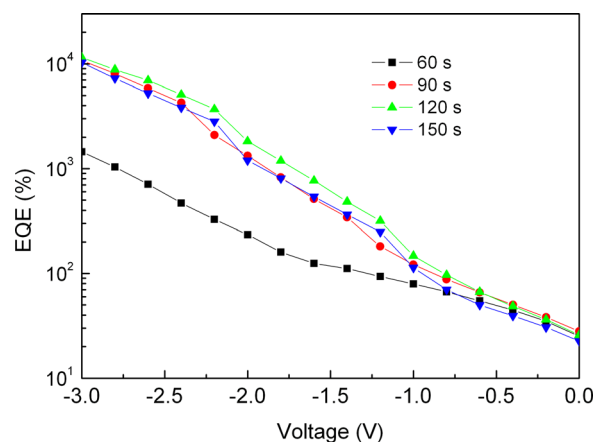


FIG. 4. EQE as a function of voltage of the ITO/Cu₂O/C₆₀/Bphen/Al hybrid devices with different Cu₂O layers.

and faster than the limit of our measurement setup of 50 ms. Besides, we have found that the photocurrent of the Cu₂O/C₆₀ hybrid UV/Vis PDs can increase linearly with the intensity of the UV light in the range from 0.038 to 1.2 mW/cm², as shown in Fig. S7 (in Ref. 40). Such a character is important for the application of PDs.

To clarify the role of Cu₂O and C₆₀ in the PDs, the photo-response of the ITO/MoO₃/C₆₀/Bphen/Al reference device at different voltages is investigated. Figure S8 (in Ref. 40) shows the EQE as a function of voltage under the illumination of the 365 nm UV light with an intensity of 1.2 mW/cm². The EQE increases from 59% at zero bias to 173% at −3 V, indicating a gain of photocurrent for this device. Similar photocurrent gain has been found in ITO/poly(3,4-ethylenedioxythiophene):poly(styrenesulfonate) (PEDOT:PSS)/C₆₀/bathocuproine/Al device by Huang and Yang, which is attributed to the disordered structure of C₆₀ and the charge trapping at the PEDOT:PSS/C₆₀ interface.⁴² However, we can also find that the gain of the reference device is significantly lower than that of Cu₂O/C₆₀ hybrid devices which exhibit EQEs as high as $1.1 \times 10^4\%$, as shown in Fig. 4. This suggests that Cu₂O may play a more important role in determining the gain of the hybrid devices.

Various types of copper vacancy, such as simple and split copper vacancies, have been proposed to exist in Cu₂O.^{33–37} Although the primary type of vacancy is still under debate, all these vacancies can act as hole traps because they introduce defect levels above the valence-band maximum of Cu₂O. One of the ways to form the copper vacancies is the outward migration of copper atoms toward the surface and finally oxidized to CuO.⁴³ Figure 5 shows the XPS spectrum of Cu₂O layer with the deposition time of 90 s. It can be found that the binding energies of the Cu 2p_{1/2} and Cu 2p_{3/2} are 953 and 933 eV, respectively, which are the characteristics of Cu⁺.⁴⁴ Meanwhile, weak satellite peaks of Cu 2p at 960 and 943 eV are observed, which are evident and diagnostic of an open 3d⁹ shell of Cu²⁺.⁴⁴ These findings indicate that the surface of Cu₂O particles is partially oxidized to CuO, which suggests that there may be a high density of copper vacancy in the Cu₂O particles. The fact that the XRD does not show evidence of CuO phase indicates that CuO is present only on the surface of Cu₂O particles. Thus the photocurrent gain of the Cu₂O/C₆₀ hybrid PDs can be understood, as shown in the

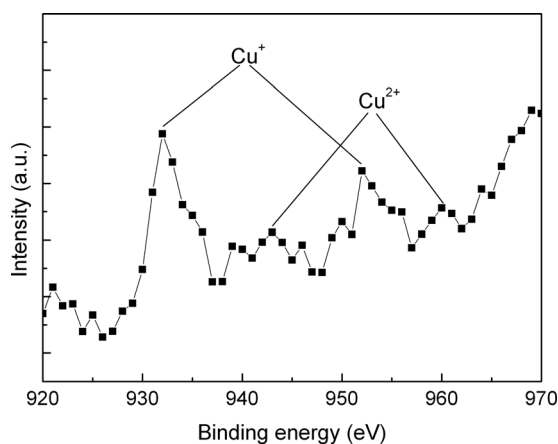


FIG. 5. XPS spectrum of 90 s Cu_2O deposited on an ITO substrate.

schematic energy band diagrams in Fig. S9 (in Ref. 40). Under dark, electron injection from ITO is blocked by Cu_2O while hole injection from Al is blocked by Bphen due to their high injection barriers. Under illumination and reverse bias, excitons form in C_{60} molecules and then dissociate to free holes and electrons at the $\text{Cu}_2\text{O}/\text{C}_{60}$ interface. The photogenerated holes are trapped by the copper vacancies in Cu_2O during their transport to ITO electrode. The trapped holes cause a large band bending, which dramatically reduces electron injection barrier from ITO and they can be tunneling injected. Since one trapped hole can trigger more than one electron injected from ITO anode, an apparent photocurrent gain is found in the $\text{Cu}_2\text{O}/\text{C}_{60}$ hybrid PDs. In view of this, we can conclude that the role of Cu_2O in these PDs is primarily to provide hole traps while C_{60} to absorb the incident photons and generate free charge carriers.

In summary, large Cu_2O particles are prepared on ITO substrate by an electrodeposition method and applied to fabricate organic/inorganic hybrid UV/Vis PDs. The simple $\text{Cu}_2\text{O}/\text{C}_{60}$ PDs present a high EQE of $1.1 \times 10^4\%$ under illumination of 365 nm UV light at -3 V, which is one of the highest values among the reported organic/inorganic hybrid UVPDs at the same wavelength and voltage. Copper vacancies are proposed as the defects in the electrodeposited Cu_2O layers. Such defects can trap photogenerated holes, which result in a decrease of electron injection barrier from ITO anode and hence the photocurrent gain of the PDs, while C_{60} only acts as a light absorption media. This provides us a design flexibility to construct Vis, near-infrared, or even panchromatic PM-type PDs by simply changing the light absorption materials. The reported high performance PDs may have the great potential to apply in a wide range of field, and this work provides a simple and low cost method to fabricate high performance PM-type PDs.

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¹M. Razeghi and A. Rogalski, *J. Appl. Phys.* **79**, 7433 (1996).

²H. Dong, H. Zhu, Q. Meng, X. Gong, and W. Hu, *Chem. Soc. Rev.* **41**, 1754 (2012).

³K. J. Baeg, M. Binda, D. Natali, M. Caironi, and Y. Y. Noh, *Adv. Mater.* **25**, 4267 (2013).

- ⁴X. Gong, M. Tong, Y. Xia, W. Cai, J. S. Moon, Y. Cao, G. Yu, C.-L. Shieh, B. Nilsson, and A. J. Heeger, *Science* **325**, 1665 (2009).
- ⁵Z. Su, W. Li, B. Chu, T. Li, J. Zhu, G. Zhang, F. Yan, X. Li, Y. Chen, and C. S. Lee, *Appl. Phys. Lett.* **93**, 103309 (2008).
- ⁶Y. Y. Lin, C. W. Chen, W. C. Yen, W. F. Su, C. H. Ku, and J. J. Wu, *Appl. Phys. Lett.* **92**, 233301 (2008).
- ⁷H. G. Li, G. Wu, M. M. Shi, L. G. Yang, H. Z. Chen, and M. Wang, *Appl. Phys. Lett.* **93**, 153309 (2008).
- ⁸L. Wang, D. Zhao, Z. Su, F. Fang, B. Li, Z. Zhang, D. Shen, and X. Wang, *Org. Electron.* **11**, 1318 (2010).
- ⁹Y. Kim, S. J. Kim, S. P. Cho, B. H. Hong, and D. J. Jang, *Sci. Rep.* **5**, 12345 (2015).
- ¹⁰Y. Jin, J. Wang, B. Sun, J. C. Blakesley, and N. C. Greenham, *Nano Lett.* **8**, 1649 (2008).
- ¹¹V. Q. Dang, T. Q. Trung, D. I. Kim, L. T. Duy, B. U. Hwang, D. W. Lee, B. Y. Kim, L. D. Toan, and N. E. Lee, *Small* **11**, 3054 (2015).
- ¹²Z. Jin, L. Gao, Q. Zhou, and J. Wang, *Sci. Rep.* **4**, 4268 (2014).
- ¹³A. Nevet, A. Hayat, and M. Orenstein, *Opt. Lett.* **36**, 725 (2011).
- ¹⁴O. Hayden, R. Agarwal, and C. M. Lieber, *Nat. Mater.* **5**, 352 (2006).
- ¹⁵D. Y. Kim, J. Ryu, J. Manders, J. Lee, and F. So, *ACS Appl. Mater. Interfaces* **6**, 1370 (2014).
- ¹⁶J. Reynaert, V. I. Arkhipov, P. Heremans, and J. Poortmans, *Adv. Funct. Mater.* **16**, 784 (2006).
- ¹⁷L. A. A. Pettersson, L. S. Roman, and O. Inganäs, *J. Appl. Phys.* **89**, 5564 (2001).
- ¹⁸M. Hiramoto, T. Imahigashi, and M. Yokoyama, *Appl. Phys. Lett.* **64**, 187 (1994).
- ¹⁹L. Li, F. Zhang, J. Wang, Q. An, Q. Sun, W. Wang, J. Zhang, and F. Teng, *Sci. Rep.* **5**, 9181 (2015).
- ²⁰W. Wang, F. Zhang, L. Li, M. Gao, and B. Hu, *ACS Appl. Mater. Interfaces* **7**, 22660 (2015).
- ²¹F. Guo, B. Yang, Y. Yuan, Z. Xiao, Q. Dong, Y. Bi, and J. Huang, *Nat. Nanotechnol.* **7**, 798 (2012).
- ²²D. Shao, M. Yu, H. Sun, G. Xin, J. Lian, and S. Sawyer, *ACS Appl. Mater. Interfaces* **6**, 14690 (2014).
- ²³Y. Fang, F. Guo, Z. Xiao, and J. Huang, *Adv. Opt. Mater.* **2**, 348 (2014).
- ²⁴R. Dong, C. Bi, Q. Dong, F. Guo, Y. Yuan, Y. Fang, Z. Xiao, and J. Huang, *Adv. Opt. Mater.* **2**, 549 (2014).
- ²⁵A. A. Hussain, A. R. Pal, and D. S. Patil, *Appl. Phys. Lett.* **104**, 193301 (2014).
- ²⁶H.-Y. Chen, M. K. F. Lo, G. Yang, H. G. Monboudewette, and Y. Yang, *Nat. Nanotechnol.* **3**, 543 (2008).
- ²⁷C. Malerba, F. Biccari, C. L. A. Ricardo, M. D'Incau, P. Scardi, and A. Mittiga, *Sol. Energy Mater. Sol. Cells* **95**, 2848 (2011).
- ²⁸X. Liu, H. Du, P. Wang, T. T. Lim, and X. W. Sun, *J. Mater. Chem. C* **2**, 9536 (2014).
- ²⁹F. A. Akgul, G. Akgul, N. Yildirim, H. E. Unalan, and R. Turan, *Mater. Chem. Phys.* **147**, 987 (2014).
- ³⁰A. Mittiga, E. Salza, F. Sarto, M. Tucci, and R. Vasanthi, *Appl. Phys. Lett.* **88**, 163502 (2006).
- ³¹M. Izaki, T. Saito, T. Ohata, K. Murata, B. M. Fariza, J. Sasano, T. Shinagawa, and S. Watase, *ACS Appl. Mater. Interfaces* **4**, 3558 (2012).
- ³²T. Minami, Y. Nishi, and T. Miyata, *Appl. Phys. Express* **8**, 022301 (2015).
- ³³O. Porat and I. Riess, *Solid State Ionics* **81**, 29 (1995).
- ³⁴D. O. Scanlon, B. J. Morgan, and G. W. Watson, *Phys. Rev. Lett.* **103**, 096405 (2009).
- ³⁵G. K. Paul, Y. Nawa, H. Sato, T. Sakurai, and K. Akimoto, *Appl. Phys. Lett.* **88**, 141901 (2006).
- ³⁶L. Y. Isseroff and E. A. Carter, *Chem. Mater.* **25**, 253 (2013).
- ³⁷Y. Yang, J. Han, X. Ning, W. Cao, W. Xu, and L. Guo, *ACS Appl. Mater. Interfaces* **6**, 22534 (2014).
- ³⁸K. P. Musselman, A. Wisnet, D. C. Iza, H. C. Hesse, C. Scheu, J. L. MacManus-Driscoll, and L. Schmidt-Mende, *Adv. Mater.* **22**, E254 (2010).
- ³⁹Y. Liu, H. K. Turley, J. R. Tumbleston, E. T. Samulski, and R. Lopez, *Appl. Phys. Lett.* **98**, 162105 (2011).
- ⁴⁰See supplementary material at <http://dx.doi.org/10.1063/1.4947581> for details about SEM, XRD, EQE, dark current, photoresponse, and schematic energy band diagrams of the devices (Figures S1–S9).
- ⁴¹M. Zhang, Irfan, H. Ding, Y. Gao, and C. W. Tang, *Appl. Phys. Lett.* **96**, 183301 (2010).
- ⁴²J. Huang and Y. Yang, *Appl. Phys. Lett.* **91**, 203505 (2007).
- ⁴³Z. Grzesik and M. Migdalska, *High Temp. Mater. Processes* **30**, 277 (2011).
- ⁴⁴M. Yin, C. K. Wu, Y. Lou, C. Burda, J. T. Koberstein, Y. Zhu, and S. O'Brien, *J. Am. Chem. Soc.* **127**, 9506 (2005).